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1AP14 Rec'd PCT/PTO 1 8 AUG 2006

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Yukihiro NAKASAKA

New U.S. Patent Application

Filed: August 18, 2006

Docket No.: 129122

For: INTAKE AIR AMOUNT VARIATION DETECTOR

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. Relevance of one or more non-English language reference is discussed in the present specification. See References 3-5 and 11.
- ☒ 3. One or more reference cited herein was cited in the International Search Report. An English language version of the International Search Report is attached for the Examiner's information. See References 6-8 and 10.
- ☒ 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- ☒ 5. A concise explanation of the relevance of one or more non-English language reference cited herein appears in the Appendix attached hereto. See References 2-5.
- ☒ 6. An English language Abstract of one or more non-English language reference is attached hereto. See References 2-6 and 8-10.
- ☒ 7. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent

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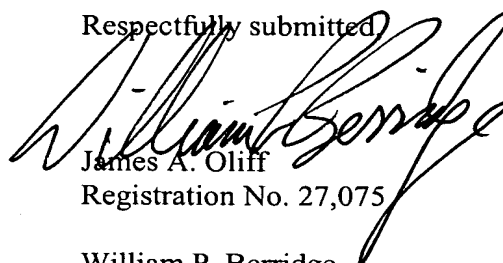
New U.S. Patent Application

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Office ([http://www.jpo.go.jp]), and is attached, but has not been reviewed for accuracy.
See References 4-8 and 10.

- ☒ 8. Reference 1 corresponds to references 9 and 7.

Respectfully submitted,



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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANTS Yukihiro NAKASAKA FILING DATE August 18, 2006			
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
	1	2003/0047166 A1	3/13/2003	Hess et al.			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	2	JP A 4-311631	11/4/1992	Japan	X		
	3	JP A 4-299084	10/22/1992	Japan	X		
	4	JP A 2004-176689	6/24/2004	Japan	X	X	
	5	JP A 5-156979	6/22/1993	Japan	X	X	
	6	JP A 9-032710	2/4/1997	Japan	X	X	
	7	JP A 2003-522878	7/29/2003	Japan		X	
	8	JP A 2004-138036	5/13/2004	Japan	X	X	
	9	WO 01/59282 A1	8/16/2001	WIPO	X		
	10	WO 2005/008052 A1	1/27/2005	WIPO	X		
	11	JP B 2831483	9/25/1999	Japan		X	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER					DATE CONSIDERED		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: August 18, 2006